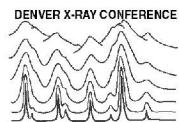


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**Table of
Contents**

**View
Document**

CONTENTS

I. TRENDS IN XRF: A WORLD PERSPECTIVE (Plenary Session)

XRF in North America	1
Donald E. Leyden	
X-Ray Fluorescence Analysis (XRF) in Europe	7
H. Ebel	
XRF in Japan and China	13
Tomoya Arai	
Personal Observations	29
Ron Jenkins	
Personal Observations	35
John V. Gilfrich	

II. XRF TECHNIQUES AND INSTRUMENTATION

X-Ray Microfluorescence of Geologic Materials	39
Dale R. Boehme	
Parameters Affecting X-Ray Microfluorescence (XRMF) Analysis	45
Monte C. Nichols, Dale R. Boehme, Richard W. Ryon, David Wherry, Brian Cross and Gary Aden	
Imaging Techniques for X-Ray Fluorescence and X-Ray Diffraction	53
N. Gurker	
X-Ray Microanalysis for Alloy Design	67
Katsumi Ohno and Michio Yamasaki	
High Spatial Resolution in X-Ray Fluorescence	77
John D. Zahrt	
Low Level Iodine Detection by TXRF in a Reactor Safety Simulation Experiment	85
F. Hegedüs, P. Winkler, P. Wobrauscheck and Christina Streli	
Robotic Automation Applied to X-Ray Fluorescence Analysis	89
J. B. Cross and R. D. Jones	

III. XRF FUNDAMENTAL PARAMETERS AND DATA ANALYSIS

Advances in Fundamental-Parameter Methods for Quantitative XRFA	97
Michael Mantler	

X-Ray Fluorescence Analysis of Geological Materials Using Rousseau's Fundamental Algorithm	105
R. G. Johnson	
Application of the Inverse Monte Carlo Method to Energy-Dispersive X-Ray Fluorescence	113
A. M. Yacout and W. L. Dunn	
Monte Carlo Simulation of the X-Ray Fluorescence Spectra From Multielement Homogeneous and Heterogeneous Samples	121
A. M. Yacout, R. P. Gardner and K. Verghese	
Quantitative Analysis of Odd-Shaped Samples by X-Ray Fluorescence Spectrometry Using Intensity Ratios	133
G. Platbrood and H. Van de Velde	
Background Intensities and their Utilization in Quantitative Analysis by Monochromatically Excited Energy-Dispersive X-Ray Fluorescence	143
Alessandra Rachetti and Wolfhard Wegscheider	
Standardless EDXRF Analysis of Cations in Ion-Exchange Resin-Impregnated Membranes	153
James R. Bogert, Jack M. Kibler and Jack K. Schmotzer	
Use of Scattered Secondary Target Radiation in EDXRF Analysis: A Fundamental-Parameter Method for Matrix Correction	165
Tom O'Reilly and Bi-Shia W. King	
Comparison of Dilution Strategies for Dealing with Unanalyzed Elements in X-Ray Fluorescence Analyses	175
Peter B. DeGroot	

IV. RECENT DEVELOPMENTS IN XRF DISPERSION DEVICES

The Use of Layered Synthetic Microstructures for Quantitative Analysis of Elements: Boron to Magnesium	183
Joseph A. Nicolosi, John P. Groven and Daryn Merlo	
The Analysis of Carbon and Other Light Elements Using Layered Synthetic Microstructures	193
John A. Anzelmo and Bradley W. Boyer	
Layered Synthetic Microstructure in Sequential and Simultaneous X-Ray Spectrometry	201
Ad van Eenbergen and Bernd Volbert	
Measurement of Soft and Ultrasoft X-Rays With Total Reflection Monochromator	213
Tomoya Arai	
Comparison of Dual-Channel Wavelength and Secondary-Target Energy-Dispersive X-Ray Spectrometers	225
John F. Croke and Joseph A. Nicolosi	

V. XRF APPLICATIONS; FUELS AND LUBRICANTS, METALS AND ALLOYS, GEOLOGICAL, HEAVY ELEMENT, OTHER	
The Efficiency of the Recessed Source Geometry for EDXRF Analysis of Metal Impurities in Oils	237
J. M. F. dos Santos, C. A. N. Conde, L. F. Requicha Ferreira and A. J. De Campos	
X-Ray Fluorescence Analysis of Sulfur and Trace Elements in Coal and Oil Tar Pitches, Asphalts and Other Bituminous Compounds	243
Vladimir Kocman	
A Comparison of Several Sample Preparation Techniques for the Analysis of Fly Ash	251
Scott Schlorholtz and Turgut Demirel	
Advances in High-Resolution Studies of the Chemical Effects in the Molybdenum L Heavy-Ion-Induced X-Ray Satellite Emission (HIXSE) Spectra	257
T. M. Rosseel, J. M. Dale, L. D. Hulett, P. L. Pepmiller, C. R. Vane, T. A. Walkiewicz and J. P. Young	
Energy Dispersive Analysis for Quality Assurance of Aluminum Alloys .	265
Yury M. Gurvich	
Multielement Preconcentration of Rare Earth Elements for their Determination at ppm-Levels in Geological Samples	273
Eva Wolf, Wolfhard Wegscheider and Hans Kolmer	
Wide Area Networking of XRF Generated Geochemical Data in a National Geological Survey	281
T. K. Smith	
Energy-Dispersive X-Ray Techniques for Accurate Heavy Element Assay .	285
H. Ottmar, H. Eberle, P. Matussek and I. Michel-Piper	
Applications of X-Ray Fluorescence Scans of Single Strands of Hair: Actual and Potential	293
Taft Y. Toribara	
Application of EDXRF Analysis to Continuous Industrial Process Monitoring	303
J. H. Weakliem and D. J. Kalnicky	
X-Ray Fluorescence Determination of Trace Elements in Complicated Matrices.	309
Lin Yawen, Fan Qinmin and Li Daolun	
An X-Ray Fluorescent Spectrometer for the Measurement of Thin Layered Materials on Silicon Wafers	315
Tomoya Arai	
Automated Quantitative XRF Analysis of Soda-Lime Glass Utilizing Pattern Recognition	325
A. J. Klimasara and T. L. Barry	

VI. QUANTITATIVE PHASE ANALYSIS BY XRD

The Use of Mass Absorption in Quantitative X-Ray Diffraction Analysis	333
Briant L. Davis and L. Ronald Johnson	
Powder Diffraction Profiles and the Pearson VII Distribution	343
Allan Brown and Sven Linde	
Observed and Calculated XRPD Intensities for Single Substance Specimens	351
Walter N. Schreiner and Giora Kimmel	
Rapid Non-Destructive X-Ray Characterization of Solid Fuels/ Propellents	357
T. S. Ananthanarayanan, W. E. Mayo, R. G. Rosemeier and R. S. Miller	
On-Stream X-Ray Diffraction Analyzer for Mineral Concentrators	365
Heikki Sipila and Jouko Koskinen	

VII. SYNCHROTRON AND NEUTRON DIFFRACTION

Lattice Parameter Determination using Synchrotron Powder Data	373
W. Parrish, M. Hart, T. C. Huang and M. Bellotto	
Synchrotron Radiation Applied to Computer Indexing	383
Gordon S. Smith, Quintin C. Johnson, David E. Cox, Robert L. Snyder Deane K. Smith, and Allan Zalkin	
Synchrotron X-Ray Scattering for the Structural Characterization of Catalysts	389
R. J. De Angelis, A. G. Dhore, M. A. Maginnis, P. J. Reucroft G. E. Ice and A. Habenschuss	
Thermal Expansion Behavior of Pure and Doped Cordierite by Time-of-Flight Neutron Diffraction	395
J. Haas, P. Predecki, J. Faber, Jr., and R. L. Hitterman	

VIII. ADVANCES IN XRD INSTRUMENTATION AND PROCEDURES

Instrumental Capabilities in X-Ray Diffraction Analysis: Comparative Techniques	407
P. J. Kincaid, R. A. Newman and T. G. Fawcett	
A New High-Temperature Camera for Diffraction Studies Above 2200°C	413
Michael Mantler and Horst Ebel	
Use of X-Ray Curved Sensitive Position Detector for Simultaneous Measurement of Several Pole Figures	421
J. J. Heizmann, C. Laruelle and A. Vadon	
A Quantitative Texture Analysis of Pluri-Crystals by Texture Goniometry	429
A. Vadon, J. J. Heizmann and C. Laruelle	

Computing X-Ray Powder Diffraction Intensities and Bragg Angles Using a Microcomputer	439
P. Sujjayakorn, H. H. Stadelmaier and J. C. Russ	

The Effects of Extinction on X-Ray Powder Diffraction Intensities	447
James P. Cline and Robert L. Snyder	

Analysis of Surface Layers and Thin Films by Low Incident Angle X-Ray Diffraction	457
S. S. Iyengar, M. W. Santana, H. Windischmann and P. Engler	

IX. HIGH TEMPERATURE AND NON-AMBIENT POWDER DIFFRACTION APPLICATIONS

X-Ray Diffraction Studies Under Non-Ambient Conditions: Application to Transition-Metal Dichalcogenide Solid Lubricants	465
E. F. Skelton, A. W. Webb, M. W. Schaefer, D. Schiferl, A. I. Katz, H. D. Hochheimer and S. B. Qadri	

High Temperature X-Ray Diffraction Study of Sol-Gel Derived $Pb(Zr_xTi_{1-x})O_3$ Powders	473
M. J. Haun, Y. H. Lee, H. A. McKinstry and L. E. Cross	

In Situ Crystallization Measurements on Fe-Zr Glasses Using an Automated High Temperature Diffractometer with a Position Sensitive Detector	483
G. Zorn, E. Hellstern, H. Gobel and L. Schultz	

Use of Dow-Developed DSC/XRD/MS in the Study of Several Model Copper-Based Catalyst Systems	493
R. A. Newman, J. A. Blazy, T. G. Fawcett, L. F. Whiting and R. A. Stowe	

Relationship Between Thermal Expansion and Crystal Chemical Parameters in Diborides	503
H. A. McKinstry, Lai Daik Chai, R. V. Sara and K. E. Spear	

X. X-RAY STRESS ANALYSIS, FRACTOGRAPHY

Experimental Methods for Determination of Precision and Estimation of Accuracy in XRD Residual Stress Measurement	511
C. O. Ruud, D. J. Snoba and D. P. Ivkovich	

Design of a Real-Time Two-Dimensional Residual Stress Analyzer	523
G. M. Borgonovi	

High Resolution Digital X-Ray Rocking Curve Topography	527
T. S. Ananthanarayanan, W. E. Mayo and R. G. Rosemeier	

X-Ray Diffraction Study of Fracture Surface Made by Fracture Toughness Tests of Blunt Notched CT Specimen of Aluminum Alloy	537
Akira Suzuki, Akira Tanji, Zenjiro Yajima, Yukio Hirose and Keisuke Tanaka	

X-Ray Fractography of Fracture Surface of Alumina Ceramics	545
Tadao Mishima, Yukio Nanayama, Yukio Hirose and Keisuke Tanaka	
XI. ANALYTICAL X-RAY SAFETY (WORKSHOP PRESENTATIONS)	
Dosimetry of X-Ray Beams: The Measure of the Problem	553
Ted de Castro	
Some Examples of Failure in X-Ray Safety	569
C. C. Lushbaugh	
Controlling Laboratory Conditions: Preventing the Problem, the Health Physicist's Viewpoint	575
Ted de Castro	
Analytical X-Ray Safety at Lawrence Livermore National Laboratory . .	583
P. L. Wallace	
Author Index	595
Subject Index	597